

Abstract

An ultra-low leakage current Application Specific Integrated Circuit (ASIC) called UtoPia (Ultralow Picoammeter) has been designed and fabricated in AMS 0.35 μm CMOS, in order to be used as the front-end for ionising radiation monitoring at CERN. It is based on the topology of a Current to Frequency Converter (CFC) and demonstrates a wide dynamic range of 8.5 decades without range changing. Due to a design aimed at minimising input leakage currents, input currents as low as 10 fA can be measured.

Keywords: radiation monitoring, ultra-low leakage current, femto-amperes

Introduction

The obligation to protect people from unjustified exposure to ionising radiation requires that **ambient radiation** be monitored.

Radiation detector: Ionisation chambers

State of the art:

Several read-out systems with wide Dynamic Range of more than 5 decades.

But $I_{\text{min}} = 300 \text{ fA}^*$ (typically among existing systems)

Limitation: Ultra-low leakage currents in the input of the ASIC

•Required radiation measurement:
50 nSv/h to 0.1 Sv/h

•Typical conversion factor for γ rays:
1.2e-6 A/Sv/h

•Required input current for a specific detector:
60 fA to 120 nA

*Flemming, H. A Successor for the GSI Charge to Frequency Converter Module, 2004.

Specifications of the front-end ASIC

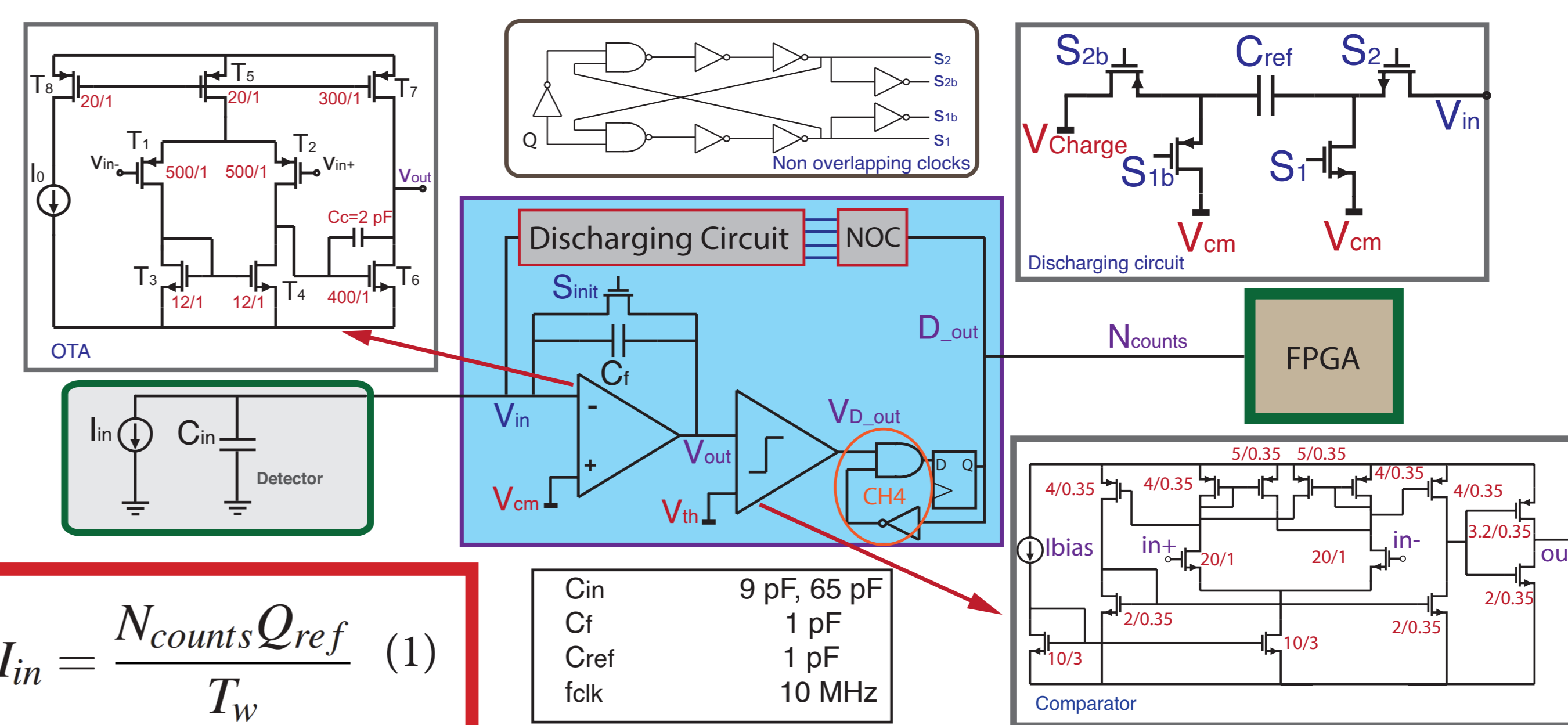
Input current polarity	Negative
Dynamic range for constant input current	60 fA to 250 nA
Maximum pulsed input current	1.72 μA
Charge per pulse	5 nC
C_{in}	9 pF, 65 pF
Measurement time window	100 ms
Linearity error	$\pm 5\%$
Temperature range	-15°C to 55°C

Utopia ASIC Architecture

Topology:

Current to Frequency Converter (CFC) Synchronous but also Asynchronous (CH4)

- The input current I_{in} is integrated in C_{in} until V_{th} is reached
- A discharging circuit injects charge Q_{ref} in the input
- If the V_{out} remains above the threshold the discharging circuit injects again (CH4)
- An FPGA counts how many times Q_{ref} is injected in a measuring time window T_w (1)



$$I_{\text{in}} = \frac{N_{\text{counts}} Q_{\text{ref}}}{T_w} \quad (1)$$

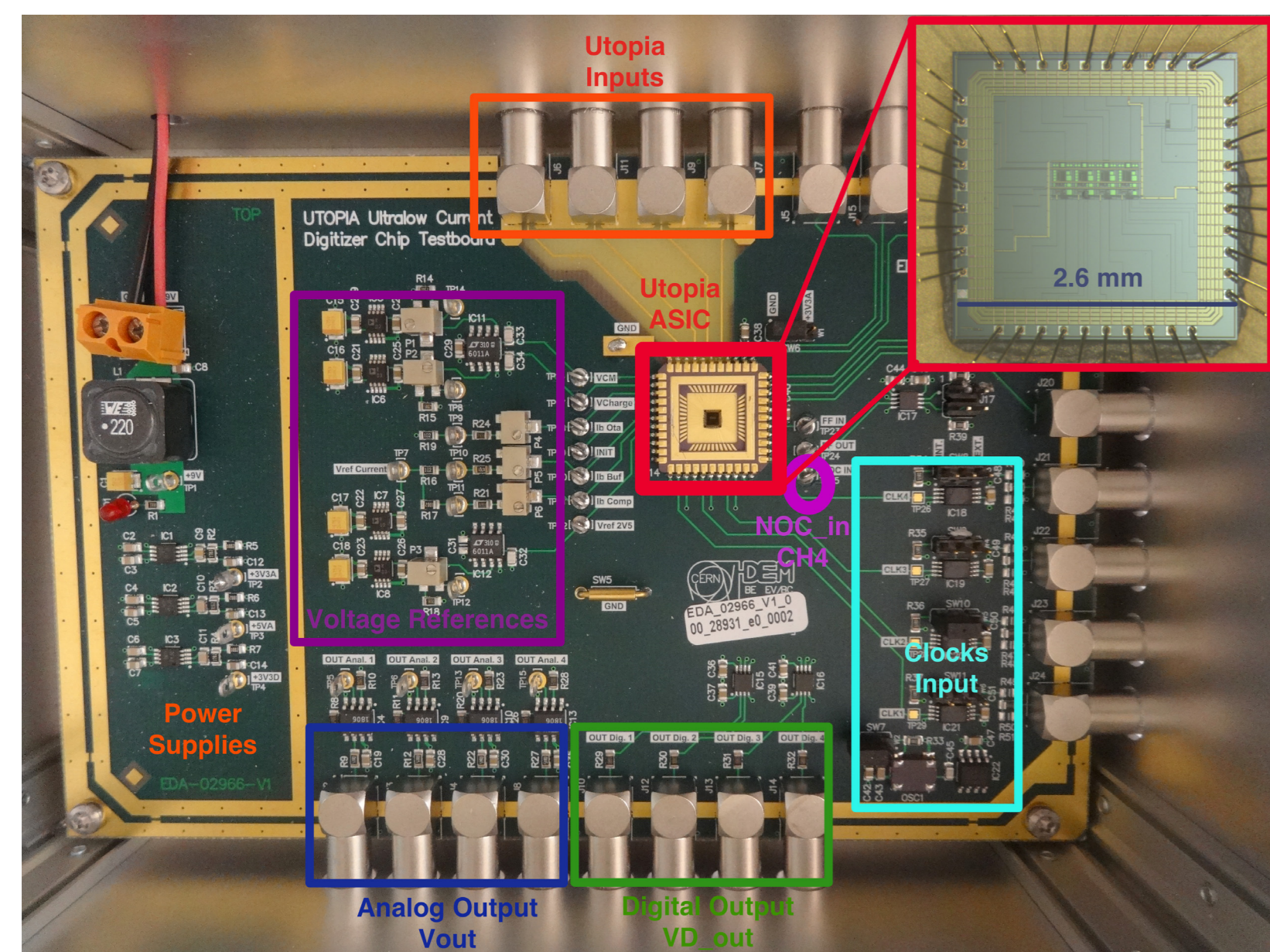
Circuit Design

AMS 0.35 μm CMOS C35B4C3 4M/2P/HR/5V IO technology
Ceramic 44 CQFJ package

- OTA: two-stage Miller amplifier with pMOS inputs
- Comparator: internal positive feedback and hysteresis
- Discharging circuit: stray insensitive switched capacitor circuit

Reference charge

$$Q_{\text{ref}} = C_{\text{ref}} V_{\text{charge}} - C_{\text{ref}} V_{\text{in}}(t) \quad (2)$$



Summary of UtoPia Characteristics

Technology	AMS 0.35 μm
Power Supply	3.3V
Clock	10MHz
Die Size	2.6mm x 2.6mm
Polarity	Negative with this biasing
Gain A_0 OTA	86dB
GBW OTA	100MHz
Phase margin ϕ OTA	62deg
Q_{ref}	1pC

Design for Ultra-low Leakage

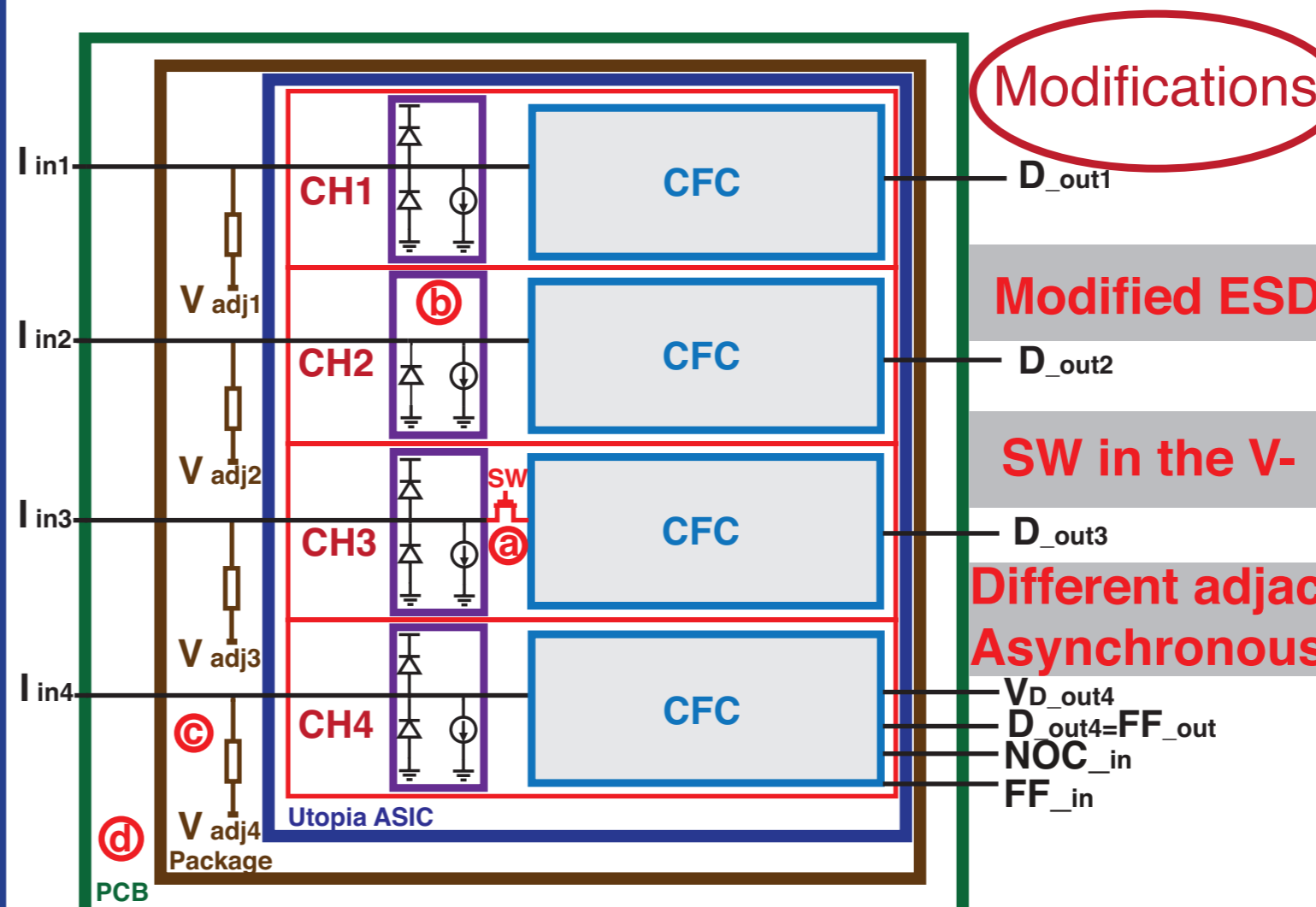
Minimum Current: $Q_{\text{ref}} = 1 \text{ pC}$, $T_w = 100 \text{ ms}$, $I_{\text{min}} = 10 \text{ pA}$

$$I_{\text{min}} = \frac{Q_{\text{ref}}}{T_w} \quad (3)$$

For measuring lower:

- The measurement time T_w can be increased
 - Averaging for better resolution
- But I_{min} is limited by the **sum of the leakage currents**

4 channels of UtoPia



(a) Subthreshold leakage current minimisation:

$$V_{TS} = V_{T0} + \gamma (\sqrt{\phi_0 + V_{SB}} - \sqrt{\phi_0}) \quad (4)$$

The V_{cm} is at a different potential relative to the bulk ($V_{\text{in}} = V_{\text{cm}} + V_{\text{out}}$)

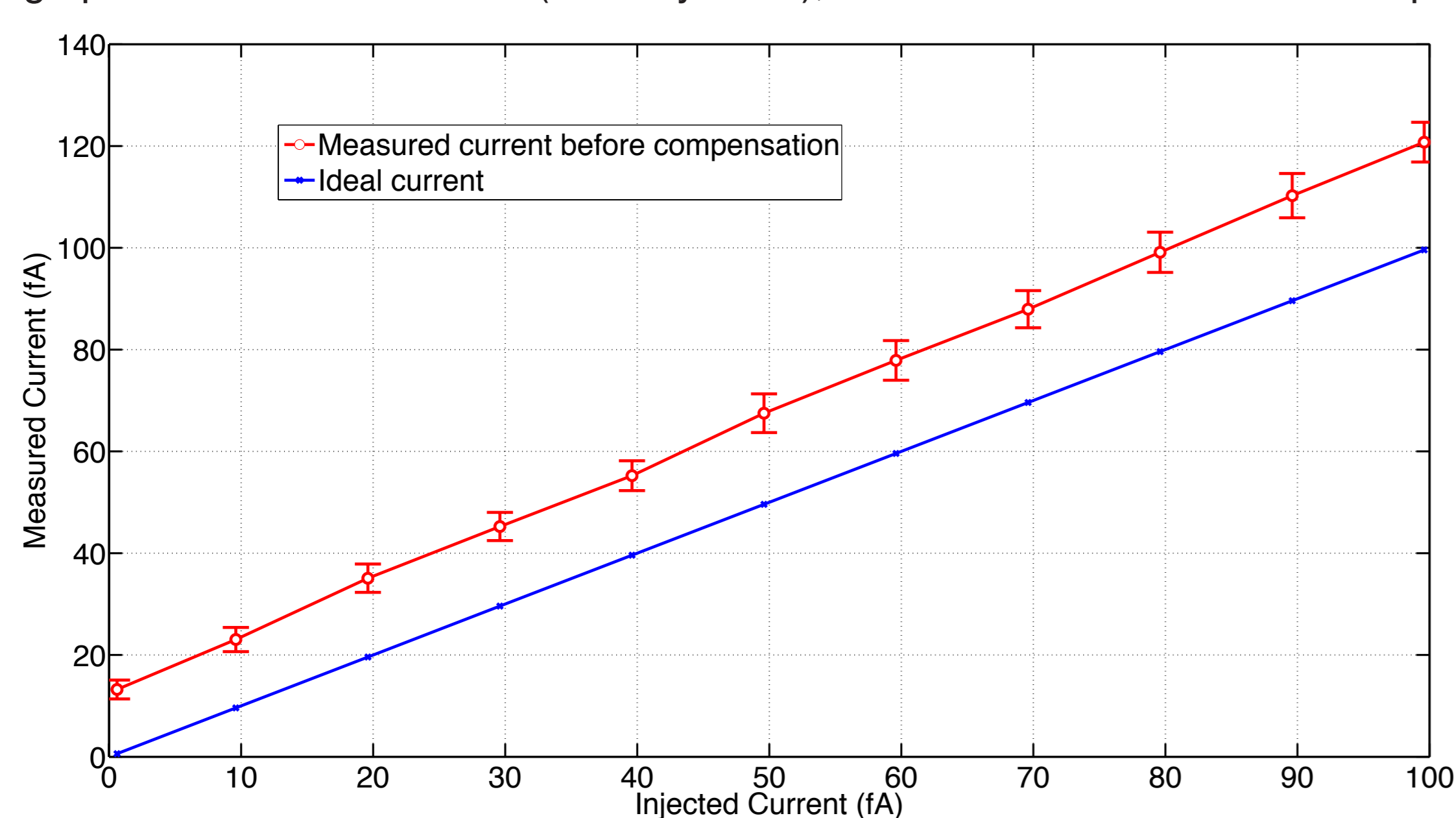
(b) ESD protection leakage current:
•Measurement over long time periods and subtraction of the offset

(c) Package leakage due to adjacent pins
Worse in CH4 that is adjacent to V_{DD} (+120 fA)
New bonding further from V_{DD} (+14 fA)

(d) PCB leakage:
Negligible, no ground plane under the inputs

fA Range Measurements

High precision current source (Keithley 6430), climatic chamber: constant temperature and humidity



Measurement time:
 $T_w = 600 \text{ s}$

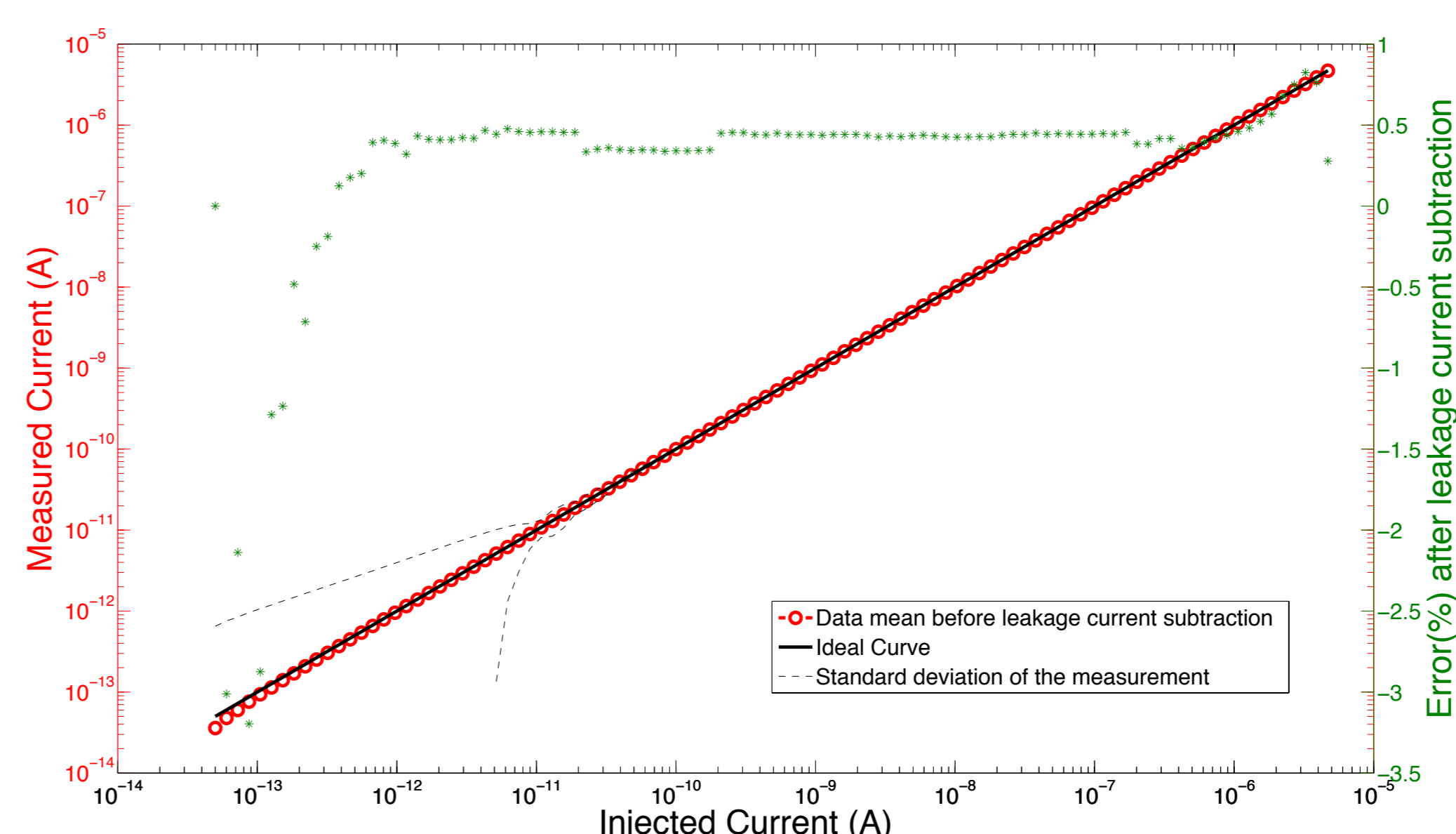
- Resolution increases
- Averaging to get non zero counts

Leakage current:
CH1, $V_{\text{cm}} = 1.62 \text{ V}$
to decrease the sum of the leakage currents

Offset of 12 fA
(same polarity)

Dynamic Range Measurements

Near the upper limit, noise on the signal pushed the system into saturation. For robustness, a control system was added to CH4 to re-inject Q_{ref} if $V_{\text{out}} > V_{\text{th}}$.



$I_{\text{max}} = 5 \mu\text{A}$

$$I_{\text{max}} = \frac{Q_{\text{ref}}}{2 \cdot T_{\text{clk}}} \quad (5)$$

Leakage current:
CH4, $V_{\text{cm}} = 1.5 \text{ V}$
Offset of 14 fA
(opposite polarity)

Conclusions:

A very wide dynamic range CFC with fA capabilities for radiation monitoring is presented. Special care was given to the input of the ASIC in order to minimise the possible sources of leakage current and be able to measure down to 10 fA after averaging over sufficient time. The ASIC is expected to work mainly in the fA to nA range. It will be revised and include auto-calibration for long term stability. Two matched channels will operate in parallel with one connected to the detector, whereas the other will integrate the ESD protection leakage current that is the dominant leakage current source. The subthreshold and package leakage currents were eliminated by design.